

#### **Product Change Notification / GBNG-17ZWEX736**

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22-Dec-2021

#### **Product Category:**

**Ethernet Controllers** 

#### **PCN Type:**

Manufacturing Change

#### **Notification Subject:**

CCB 4959 Initial Notice: Qualification of MMT as a new assembly site for selected SMSC LAN91C11xx device family available in 128L TQFP (14x14x1mm) package.

#### **Affected CPNs:**

GBNG-17ZWEX736\_Affected\_CPN\_12222021.pdf GBNG-17ZWEX736\_Affected\_CPN\_12222021.csv

#### **Notification Text:**

PCN Status:Initial Notification

**PCN Type:**Manufacturing Change

**Microchip Parts Affected:**Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

**Description of Change:**Qualification of MMT as a new assembly site for selected SMSC LAN91C11xx device family available in 128L TQFP (14x14x1mm) package.

#### **Pre and Post Change Summary:**

|                              | Pre CI            | nange         | Post Change           |  |   |  |
|------------------------------|-------------------|---------------|-----------------------|--|---|--|
| Assembly Site                | ASE Inc.<br>(ASE) |               |                       |  | Microchip Technology<br>Thailand<br>(MMT) |  |
| Wire Material                | Au PdCu           |               | CuPdAu                |  |   |  |
|                              | 1076WA            |               |                       |  |   |  |
| Die Attach Material          | 1076              | OVVA          | 3280                  |  |   |  |
| Molding Compound<br>Material | G631H             |               | G700HA                |  |   |  |
| Lead-Frame Material          | C7025             |               | C7025                 |  |   |  |
| Lead-Frame Paddle Size       | 240 x 240 mils    |               | 252 x 252 mils        |  |   |  |
| DAP Surface Prep             | Doubl             | e Ring        | Bare Cu               |  |   |  |
| Lead-Frame Design            | See attac         | hed Pre and P | ost Change comparison |  |   |  |

Impacts to Data Sheet:None

#### Change ImpactNone

**Reason for Change:**To improve on-time delivery performance by qualifying MMT as a new assembly site.

**Change Implementation Status:**In Progress

#### **Estimated Qualification Completion Date:**March 2022

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

#### **Time Table Summary:**

|                             | December 2021 |        |        |        | >      | March 2022 |        |        |     |     |        |
|-----------------------------|---------------|--------|--------|--------|--------|------------|--------|--------|-----|-----|--------|
| Workweek                    | 4<br>9        | 5<br>0 | 5<br>1 | 5<br>2 | 5<br>3 |            | 1<br>0 | 1<br>1 | 1 2 | 1 3 | 1<br>4 |
| Initial PCN Issue<br>Date   |               |        |        | Х      |        |            |        |        |     |     |        |
| Qual Report<br>Availability |               |        |        |        |        |            | Х      |        |     |     |        |
| Final PCN Issue<br>Date     |               |        |        |        |        |            |        |        |     | Х   |        |

Method to Identify Change: Traceability code

**Qualification Plan:** Please open the attachments included with this PCN labeled as PCN\_#\_Qual\_Plan.

**Revision History:**December 22, 2021: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

#### **Attachments:**

PCN\_GBNG-17ZWEX736\_Qual\_Plan.pdf PCN\_GBNG-17ZWEX736\_Pre and Post Change\_Summary.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

#### **Terms and Conditions:**

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

| GBNG-17ZWEX736 - CCB 4959 Initial Notice: Qualification of MMT as a new assembly site for selected SMSC LAN91C11xx device family available in 128L TQFP (14x14x1mm) package. |
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| Affected Catalog Part Numbers (CPN)  |
| LAN91C113-NU<br>LAN91C111-NU   |
| LAN91C11II-NU  |
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| Date: Wednesday, December 22, 2021   |

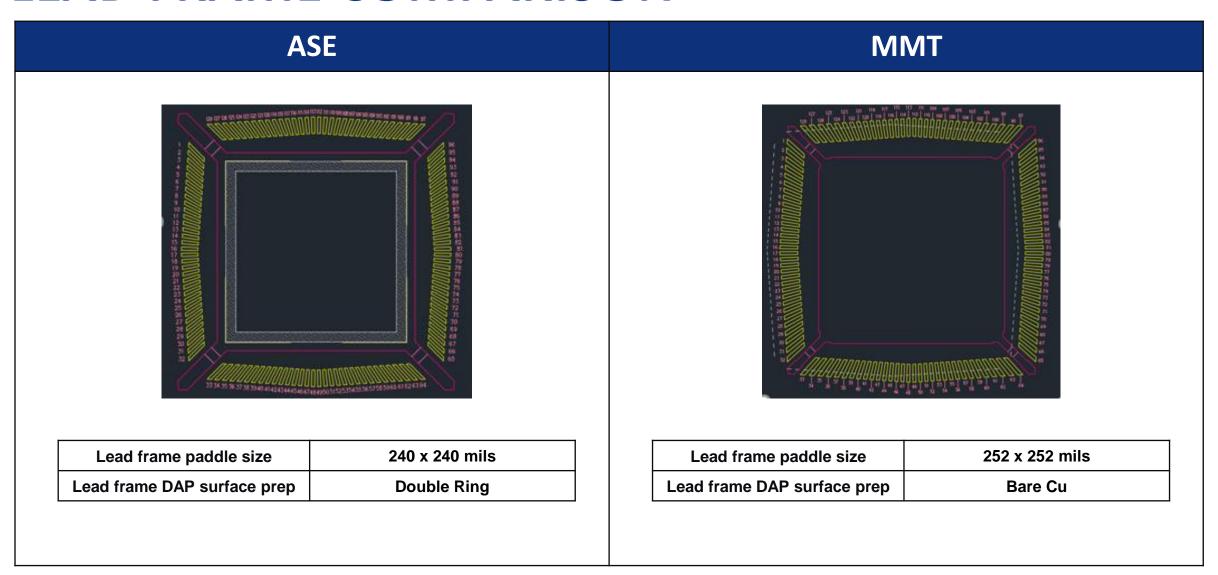
# CCB 4959 Pre and Post Change Summary PCN #: GBNG-17ZWEX736



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### **LEAD FRAME COMPARISON**







#### **QUALIFICATION PLAN SUMMARY**

**PCN #: GBNG-17ZWEX736** 

Date: December 9, 2021

Qualification of MMT as a new assembly site for selected SMSC LAN91C11xx device family available in 128L TQFP (14x14x1mm) package.

## Purpose: Qualification of MMT as a new assembly site for selected SMSC LAN91C11xx device family available in 128L TQFP (14x14x1mm) package.

#### CCB No. 4959

| Assembly site                            | MMT           |
|--|---------------|
| BD Number                                | BD-000268/02  |
| MP Code (MPC)                            | UA0027Z2XA00  |
| Part Number (CPN)                        | LAN91C111I-NU |
| MSL information                          | 3             |
| Assembly Shipping Media (T/R, Tube/Tray) | Tray          |
| Base Quantity Multiple (BQM)             | 90            |
| Reliability Site                         | MTAI          |
| Paddle size                              | 252x252 mils  |
| Lead frame Material                      | C7025         |
| DAP Surface Prep                         | Bare Cu       |
| Treatment                                | ВОТ           |
| Process                                  | Etched        |
| Lead-lock                                | Yes           |
| Part Number                              | 10112802      |
| Lead Plating                             | Matte tin     |
| Wire Material                            | CuPdAu        |
| Die Attach Material                      | 3280          |
| Conductive                               | Yes           |
| Molding Compound Material                | G700HA        |
| PKG Type                                 | TQFP          |
| Pin/Ball Count                           | 128           |
| PKG width/size                           | 14x14 mm      |

| Test Name                         | Conditions   | Sample<br>Size   | Min. Qty of<br>Spares<br>per Lot<br>(should be<br>properly<br>marked) | Qty<br>of<br>Lots | Total<br>Units | Fail<br>Accept<br>Qty     | Est.<br>Dur.<br>Days | Special Instructions  |
|-----------------------------------|--|--|---|-------------------|----------------|---------------------------|----------------------|---|
| Standard Pb-free<br>Solderability | J-STD-002D; Perform 8 hour steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing.  Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages. | 22   | 5   | 1                 | 27             | > 95%<br>lead<br>coverage | 5                    | Standard Pb-free solderability is the requirement.  SnPb solderability (backward solderability- SMD                 |
| Backward Solderability            | J-STD-002D; Perform 8 hours steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing.  Backward: Matte tin/ NiPdAu finish, SnPb solder, wetting temp 215°C for SMD.                                    | 22   | 5   | 1                 | 27             | > 95%<br>lead<br>coverage | 5                    | reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes. |
| Wire Bond Pull - WBP              | Mil. Std. 883-2011   | 5  | 0   | 1                 | 5              | 0 fails<br>after TC       | 5                    | 30 bonds from a min. 5 devices.   |
| Wire Bond Shear - WBS             | CDF-AEC-Q100-001   | 5  | 0   | 1                 | 5              |                           | 5                    | 30 bonds from a min. 5 devices.   |
| Wire Sweep                        |  |  |   |                   |                |                           |                      | Required for any reduction in wire bond thickness.  |
| Physical Dimensions               | Measure per JESD22 B100 and B108   | 10   | 0   | 3                 | 30             |                           | 5                    |   |
| External Visual                   | Mil. Std. 883-2009/2010  | All devices<br>prior to<br>submission<br>for<br>qualification<br>testing | 0   | 3                 | ALL            | 0                         | 5                    |   |

| Test Name  | Conditions   | Sample<br>Size | Min. Qty of<br>Spares<br>per Lot<br>(should be<br>properly<br>marked) | Qty<br>of<br>Lots | Total<br>Units | Fail<br>Accept<br>Qty | Est.<br>Dur.<br>Days | Special Instructions   |
|--|--|----------------|---|-------------------|----------------|-----------------------|----------------------|--|
| Preconditioning - Required for surface mount devices | +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type; Electrical test pre and post stress at +25°C.  MSL3/260C | 231            | 15  | 3                 | 738            | 0                     | 15                   | Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test.  |
| HAST   | +130°C/85% RH for 96 hours. Electrical test pre and post stress at +25°C and hot temp.  Extend to 192 hrs post test at 25C   | 77             | 5   | 3                 | 246            | 0                     | 10                   | Spares should be properly identified. Use the parts which have gone through Preconditioning.  Perform 2X extended reliability testing for Cu bond wire related package qual.  For Automotive Cu wire qual, refer to Q006 Auto Cu Qual plan (Form 1.1). |
| UHAST  | +130°C/85% RH for 96 hrs. Electrical test pre and post stress at +25°C Extend to 192 hrs post test at 25C  | 77             | 5   | 3                 | 246            | 0                     | 10                   | Spares should be properly identified. Use the parts which have gone through Preconditioning.  Perform 2X extended reliability testing for Cu bond wire related package qual.  For Automotive Cu wire qual, refer to Q006 Auto Cu Qual plan (Form 1.1). |
| Temp Cycle   | -65°C to +150°C for 500 cycles.  Electrical test pre and post stress at hot temp; 3 grams force WBP, on 5 devices from 1 lot, test following Temp Cycle stress.  Extend to 1000 cycle Post test at 25°C    | 77             | 5   | 3                 | 246            | 0                     | 15                   | Spares should be properly identified. Use the parts which have gone through Preconditioning.  Perform 2X extended reliability testing for Cu bond wire related package qual.  For Automotive Cu wire qual, refer to Q006 Auto Cu Qual plan (Form 1.1). |